

<b>Notice of References Cited</b>	Application/Control No. 10/690,196	Applicant(s)/Patent Under Reexamination GARDELLA ET AL.	
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**U.S. PATENT DOCUMENTS**

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	U	Saito et al. "TOF-SIMS analysis of chemical state changes in cresol-novolac photoresist surface caused by O <sub>2</sub> plasma downstream", Applied Surface Science (1999), 142(1-4), 460-464
	V	Davies et al. "Probing the surface chemical structure of some novel poly(ortho esters) prepared with N-methyl and N-phenyl ethanolamine by ... (ToF-SIMS)", Polymers for Advanced Technologies, September 1999, v. 3, pp. 293-301
	W	Chen et al. "Time-of-Flight Secondary Ion Mass Spectrometry studies of in vitro hydrolytic degradation of biodegradable polymers", Macromolecules, 1999, v. 32, pp. 7380-7388
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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	U	Davies et al. "Probing the surface chemical structure of some novel poly(ortho esters) prepared with N-methyl- and N-phenylethanolamine by time-of-flight secondary ion mass spectrometry (ToF-SIMS)", Polymers for Advanced Technologies (1992), 3(6), 293-301
	V	Short et al. "TOF SIMS in polymer surface studies", Vacuum (1993), 44(11-12), 1143-60
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